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## Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

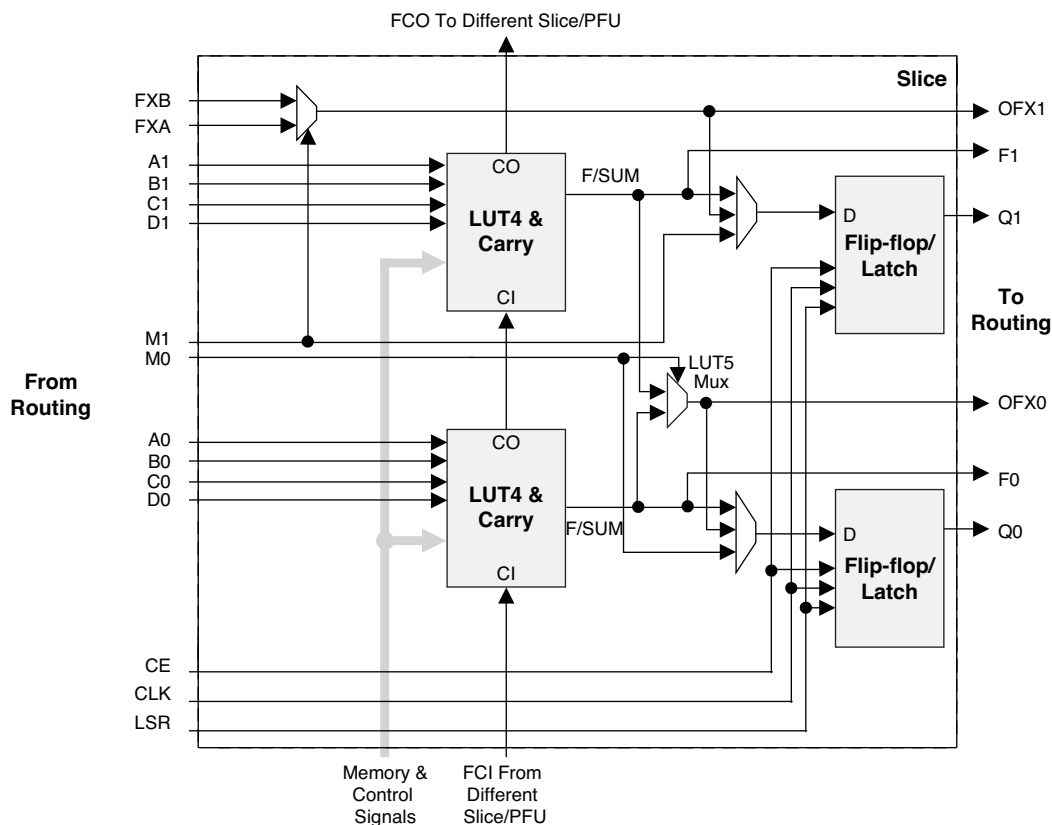
## Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

### Details

Product Status	Active
Number of LABs/CLBs	32
Number of Logic Elements/Cells	256
Total RAM Bits	-
Number of I/O	40
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	48-QFNS (7x7)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-256hc-6sg48c">https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-256hc-6sg48c</a>

**Figure 2-4. Slice Diagram**



For Slices 0 and 1, memory control signals are generated from Slice 2 as follows:

- WCK is CLK
- WRE is from LSR
- DI[3:2] for Slice 1 and DI[1:0] for Slice 0 data from Slice 2
- WAD [A:D] is a 4-bit address from slice 2 LUT input

**Table 2-2. Slice Signal Descriptions**

Function	Type	Signal Names	Description
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4
Input	Multi-purpose	M0/M1	Multi-purpose input
Input	Control signal	CE	Clock enable
Input	Control signal	LSR	Local set/reset
Input	Control signal	CLK	System clock
Input	Inter-PFU signal	FCIN	Fast carry in <sup>1</sup>
Output	Data signals	F0, F1	LUT4 output register bypass signals
Output	Data signals	Q0, Q1	Register outputs
Output	Data signals	OFX0	Output of a LUT5 MUX
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8 <sup>2</sup> MUX depending on the slice
Output	Inter-PFU signal	FCO	Fast carry out <sup>1</sup>

1. See Figure 2-3 for connection details.

2. Requires two PFUs.

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## ROM Mode

ROM mode uses the LUT logic; hence, slices 0-3 can be used in ROM mode. Preloading is accomplished through the programming interface during PFU configuration.

For more information on the RAM and ROM modes, please refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

## Routing

There are many resources provided in the MachXO2 devices to route signals individually or as buses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments.

The inter-PFU connections are made with three different types of routing resources: x1 (spans two PFUs), x2 (spans three PFUs) and x6 (spans seven PFUs). The x1, x2, and x6 connections provide fast and efficient connections in the horizontal and vertical directions.

The design tools take the output of the synthesis tool and places and routes the design. Generally, the place and route tool is completely automatic, although an interactive routing editor is available to optimize the design.

## Clock/Control Distribution Network

Each MachXO2 device has eight clock inputs (PCLK [T, C] [Banknum]\_[2..0]) – three pins on the left side, two pins each on the bottom and top sides and one pin on the right side. These clock inputs drive the clock nets. These eight inputs can be differential or single-ended and may be used as general purpose I/O if they are not used to drive the clock nets. When using a single ended clock input, only the PCLKT input can drive the clock tree directly.

The MachXO2 architecture has three types of clocking resources: edge clocks, primary clocks and secondary high fanout nets. MachXO2-640U, MachXO2-1200/U and higher density devices have two edge clocks each on the top and bottom edges. Lower density devices have no edge clocks. Edge clocks are used to clock I/O registers and have low injection time and skew. Edge clock inputs are from PLL outputs, primary clock pads, edge clock bridge outputs and CIB sources.

The eight primary clock lines in the primary clock network drive throughout the entire device and can provide clocks for all resources within the device including PFUs, EBRs and PICs. In addition to the primary clock signals, MachXO2 devices also have eight secondary high fanout signals which can be used for global control signals, such as clock enables, synchronous or asynchronous clears, presets, output enables, etc. Internal logic can drive the global clock network for internally-generated global clocks and control signals.

The maximum frequency for the primary clock network is shown in the MachXO2 External Switching Characteristics table.

The primary clock signals for the MachXO2-256 and MachXO2-640 are generated from eight 17:1 muxes. The available clock sources include eight I/O sources and 9 routing inputs. Primary clock signals for the MachXO2-640U, MachXO2-1200/U and larger devices are generated from eight 27:1 muxes. The available clock sources include eight I/O sources, 11 routing inputs, eight clock divider inputs and up to eight sysCLOCK PLL outputs.

**Figure 2-6. Secondary High Fanout Nets for MachXO2 Devices**



## sysCLOCK Phase Locked Loops (PLLs)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The MachXO2-640U, MachXO2-1200/U and larger devices have one or more sysCLOCK PLL. CLKI is the reference frequency input to the PLL and its source can come from an external I/O pin or from internal routing. CLKFB is the feedback signal to the PLL which can come from internal routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The MachXO2 sysCLOCK PLLs support high resolution (16-bit) fractional-N synthesis. Fractional-N frequency synthesis allows the user to generate an output clock which is a non-integer multiple of the input frequency. For more information about using the PLL with Fractional-N synthesis, please see TN1199, [MachXO2 sysCLOCK PLL Design and Usage Guide](#).

Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The output dividers may also be cascaded together to generate low frequency clocks. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the MachXO2 clock distribution network directly or general purpose routing resources can be used.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected. A block diagram of the PLL is shown in Figure 2-7.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock.



## PIO

The PIO contains three blocks: an input register block, output register block and tri-state register block. These blocks contain registers for operating in a variety of modes along with the necessary clock and selection logic.

**Table 2-8. PIO Signal List**

Pin Name	I/O Type	Description
CE	Input	Clock Enable
D	Input	Pin input from sysIO buffer.
INDD	Output	Register bypassed input.
INCK	Output	Clock input
Q0	Output	DDR positive edge input
Q1	Output	Registered input/DDR negative edge input
D0	Input	Output signal from the core (SDR and DDR)
D1	Input	Output signal from the core (DDR)
TD	Input	Tri-state signal from the core
Q	Output	Data output signals to sysIO Buffer
TQ	Output	Tri-state output signals to sysIO Buffer
DQSR90 <sup>1</sup>	Input	DQS shift 90-degree read clock
DQSW90 <sup>1</sup>	Input	DQS shift 90-degree write clock
DDRCLKPOL <sup>1</sup>	Input	DDR input register polarity control signal from DQS
SCLK	Input	System clock for input and output/tri-state blocks.
RST	Input	Local set reset signal

1. Available in PIO on right edge only.

### Input Register Block

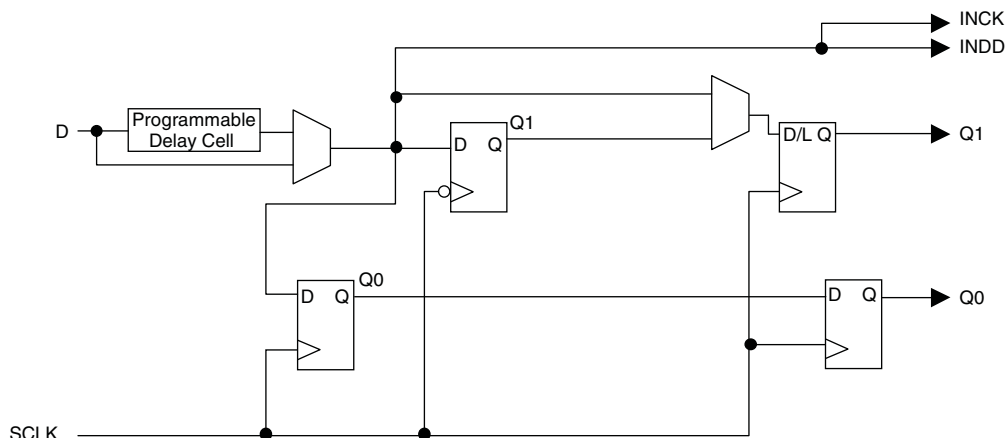
The input register blocks for the PIOs on all edges contain delay elements and registers that can be used to condition high-speed interface signals before they are passed to the device core. In addition to this functionality, the input register blocks for the PIOs on the right edge include built-in logic to interface to DDR memory.

Figure 2-12 shows the input register block for the PIOs located on the left, top and bottom edges. Figure 2-13 shows the input register block for the PIOs on the right edge.

#### Left, Top, Bottom Edges

Input signals are fed from the sysIO buffer to the input register block (as signal D). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), and a clock (INCK). If an input delay is desired, users can select a fixed delay. I/Os on the bottom edge also have a dynamic delay, DEL[4:0]. The delay, if selected, reduces input register hold time requirements when using a global clock. The input block allows two modes of operation. In single data rate (SDR) the data is registered with the system clock (SCLK) by one of the registers in the single data rate sync register block. In Generic DDR mode, two registers are used to sample the data on the positive and negative edges of the system clock (SCLK) signal, creating two data streams.

**Figure 2-12. MachXO2 Input Register Block Diagram (PIO on Left, Top and Bottom Edges)**



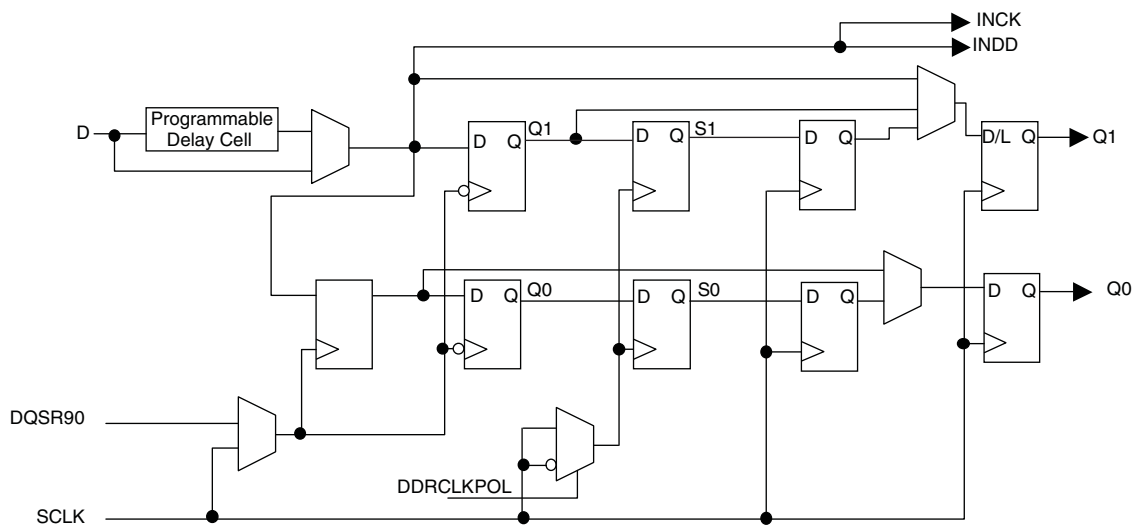
### Right Edge

The input register block on the right edge is a superset of the same block on the top, bottom, and left edges. In addition to the modes described above, the input register block on the right edge also supports DDR memory mode.

In DDR memory mode, two registers are used to sample the data on the positive and negative edges of the modified DQS (DQSR90) in the DDR Memory mode creating two data streams. Before entering the core, these two data streams are synchronized to the system clock to generate two data streams.

The signal DDRCLKPOL controls the polarity of the clock used in the synchronization registers. It ensures adequate timing when data is transferred to the system clock domain from the DQS domain. The DQSR90 and DDRCLKPOL signals are generated in the DQS read-write block.

**Figure 2-13. MachXO2 Input Register Block Diagram (PIO on Right Edge)**



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## Configuration and Testing

This section describes the configuration and testing features of the MachXO2 family.

### IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with  $V_{CCIO}$  Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#) and TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#).

### Device Configuration

All MachXO2 devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I<sup>2</sup>C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO2 device:

1. Internal Flash Download
2. JTAG
3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory
4. System microprocessor to drive a serial slave SPI port (SSPI mode)
5. Standard I<sup>2</sup>C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1204, [MachXO2 Programming and Configuration Usage Guide](#) for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO2 devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip Flash memory, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip Flash memory. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

### TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) for details.



### Static Supply Current – ZE Devices<sup>1, 2, 3, 6</sup>

Symbol	Parameter	Device	Typ. <sup>4</sup>	Units
$I_{CC}$	Core Power Supply	LCMXO2-256ZE	18	$\mu A$
		LCMXO2-640ZE	28	$\mu A$
		LCMXO2-1200ZE	56	$\mu A$
		LCMXO2-2000ZE	80	$\mu A$
		LCMXO2-4000ZE	124	$\mu A$
		LCMXO2-7000ZE	189	$\mu A$
$I_{CCIO}$	Bank Power Supply <sup>5</sup> $V_{CCIO} = 2.5 V$	All devices	1	$\mu A$

1. For further information on supply current, please refer to TN1198, [Power Estimation and Management for MachXO2 Devices](#).
2. Assumes blank pattern with the following characteristics: all outputs are tri-stated, all inputs are configured as LVCMOS and held at  $V_{CCIO}$  or GND, on-chip oscillator is off, on-chip PLL is off. To estimate the impact of turning each of these items on, please refer to the following table or for more detail with your specific design use the Power Calculator tool.
3. Frequency = 0 MHz.
4.  $T_J = 25^\circ C$ , power supplies at nominal voltage.
5. Does not include pull-up/pull-down.
6. To determine the MachXO2 peak start-up current data, use the Power Calculator tool.

### Static Power Consumption Contribution of Different Components – ZE Devices

The table below can be used for approximating static power consumption. For a more accurate power analysis for your design please use the Power Calculator tool.

Symbol	Parameter	Typ.	Units
$I_{DCBG}$	Bandgap DC power contribution	101	$\mu A$
$I_{DCPOR}$	POR DC power contribution	38	$\mu A$
$I_{DCIOBANKCONTROLLER}$	DC power contribution per I/O bank controller	143	$\mu A$

**Programming and Erase Flash Supply Current – ZE Devices<sup>1, 2, 3, 4</sup>**

Symbol	Parameter	Device	Typ. <sup>5</sup>	Units
$I_{CC}$	Core Power Supply	LCMXO2-256ZE	13	mA
		LCMXO2-640ZE	14	mA
		LCMXO2-1200ZE	15	mA
		LCMXO2-2000ZE	17	mA
		LCMXO2-4000ZE	18	mA
		LCMXO2-7000ZE	20	mA
$I_{CCIO}$	Bank Power Supply <sup>6</sup>	All devices	0	mA

1. For further information on supply current, please refer to TN1198, [Power Estimation and Management for MachXO2 Devices](#).

2. Assumes all inputs are held at  $V_{CCIO}$  or GND and all outputs are tri-stated.

3. Typical user pattern.

4. JTAG programming is at 25 MHz.

5.  $T_J = 25^\circ\text{C}$ , power supplies at nominal voltage.

6. Per bank.  $V_{CCIO} = 2.5\text{ V}$ . Does not include pull-up/pull-down.

Input/Output Standard	$V_{IL}$		$V_{IH}$		$V_{OL}$ Max. (V)	$V_{OH}$ Min. (V)	$I_{OL}$ Max. <sup>4</sup> (mA)	$I_{OH}$ Max. <sup>4</sup> (mA)
	Min. (V) <sup>3</sup>	Max. (V)	Min. (V)	Max. (V)				
LVC MOS10R25	-0.3	$V_{REF} - 0.1$	$V_{REF} + 0.1$	3.6	0.40	NA Open Drain	16, 12, 8, 4	NA Open Drain

1. MachXO2 devices allow LVC MOS inputs to be placed in I/O banks where  $V_{CCIO}$  is different from what is specified in the applicable JEDEC specification. This is referred to as a ratioed input buffer. In a majority of cases this operation follows or exceeds the applicable JEDEC specification. The cases where MachXO2 devices do not meet the relevant JEDEC specification are documented in the table below.
2. MachXO2 devices allow for LVC MOS referenced I/Os which follow applicable JEDEC specifications. For more details about mixed mode operation please refer to please refer to TN1202, [MachXO2 sysIO Usage Guide](#).
3. The dual function I<sup>2</sup>C pins SCL and SDA are limited to a  $V_{IL}$  min of -0.25 V or to -0.3 V with a duration of <10 ns.
4. For electromigration, the average DC current sourced or sinked by I/O pads between two consecutive  $V_{CCIO}$  or GND pad connections, or between the last  $V_{CCIO}$  or GND in an I/O bank and the end of an I/O bank, as shown in the Logic Signal Connections table (also shown as I/O grouping) shall not exceed a maximum of  $n * 8$  mA. "n" is the number of I/O pads between the two consecutive bank  $V_{CCIO}$  or GND connections or between the last  $V_{CCIO}$  and GND in a bank and the end of a bank. IO Grouping can be found in the Data Sheet Pin Tables, which can also be generated from the Lattice Diamond software.

Input Standard	$V_{CCIO}$ (V)	$V_{IL}$ Max. (V)
LVC MOS 33	1.5	0.685
LVC MOS 25	1.5	0.687
LVC MOS 18	1.5	0.655

## sysIO Differential Electrical Characteristics

The LVDS differential output buffers are available on the top side of MachXO2-640U, MachXO2-1200/U and higher density devices in the MachXO2 PLD family.

## LVDS

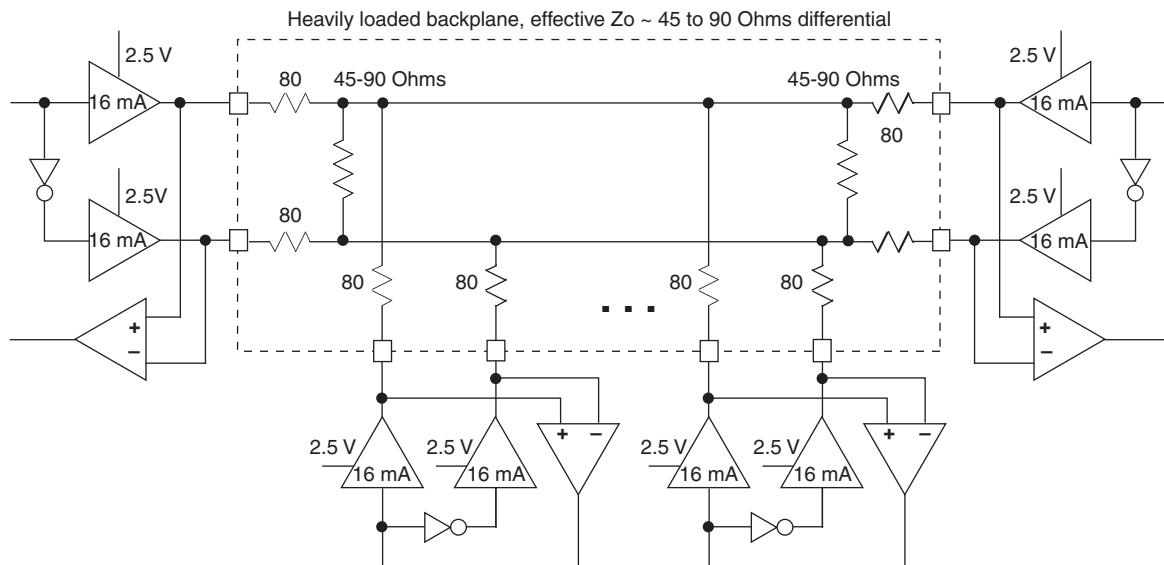
### Over Recommended Operating Conditions

Parameter Symbol	Parameter Description	Test Conditions	Min.	Typ.	Max.	Units
$V_{INP}$ $V_{INM}$	Input Voltage	$V_{CCIO} = 3.3$ V	0	—	2.605	V
		$V_{CCIO} = 2.5$ V	0	—	2.05	V
$V_{THD}$	Differential Input Threshold		±100	—		mV
$V_{CM}$	Input Common Mode Voltage	$V_{CCIO} = 3.3$ V	0.05	—	2.6	V
		$V_{CCIO} = 2.5$ V	0.05	—	2.0	V
$I_{IN}$	Input current	Power on	—	—	±10	μA
$V_{OH}$	Output high voltage for $V_{OP}$ or $V_{OM}$	$R_T = 100$ Ohm	—	1.375	—	V
$V_{OL}$	Output low voltage for $V_{OP}$ or $V_{OM}$	$R_T = 100$ Ohm	0.90	1.025	—	V
$V_{OD}$	Output voltage differential	$(V_{OP} - V_{OM})$ , $R_T = 100$ Ohm	250	350	450	mV
$\Delta V_{OD}$	Change in $V_{OD}$ between high and low		—	—	50	mV
$V_{OS}$	Output voltage offset	$(V_{OP} + V_{OM})/2$ , $R_T = 100$ Ohm	1.125	1.20	1.395	V
$\Delta V_{OS}$	Change in $V_{OS}$ between H and L		—	—	50	mV
$I_{OSD}$	Output short circuit current	$V_{OD} = 0$ V driver outputs shorted	—	—	24	mA

### BLVDS

The MachXO2 family supports the BLVDS standard through emulation. The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs. The input standard is supported by the LVDS differential input buffer. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.

**Figure 3-2. BLVDS Multi-point Output Example**



**Table 3-2. BLVDS DC Conditions<sup>1</sup>**

#### Over Recommended Operating Conditions

Symbol	Description	Nominal		Units
		Zo = 45	Zo = 90	
Z <sub>OUT</sub>	Output impedance	20	20	Ohms
R <sub>S</sub>	Driver series resistance	80	80	Ohms
R <sub>TLEFT</sub>	Left end termination	45	90	Ohms
R <sub>TRIGHT</sub>	Right end termination	45	90	Ohms
V <sub>OH</sub>	Output high voltage	1.376	1.480	V
V <sub>OL</sub>	Output low voltage	1.124	1.020	V
V <sub>OD</sub>	Output differential voltage	0.253	0.459	V
V <sub>CM</sub>	Output common mode voltage	1.250	1.250	V
I <sub>DC</sub>	DC output current	11.236	10.204	mA

1. For input buffer, see LVDS table.

## Typical Building Block Function Performance – ZE Devices<sup>1</sup>

### Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	–3 Timing	Units
<b>Basic Functions</b>		
16-bit decoder	13.9	ns
4:1 MUX	10.9	ns
16:1 MUX	12.0	ns

### Register-to-Register Performance

Function	–3 Timing	Units
<b>Basic Functions</b>		
16:1 MUX	191	MHz
16-bit adder	134	MHz
16-bit counter	148	MHz
64-bit counter	77	MHz
<b>Embedded Memory Functions</b>		
1024x9 True-Dual Port RAM (Write Through or Normal, EBR output registers)	90	MHz
<b>Distributed Memory Functions</b>		
16x4 Pseudo-Dual Port RAM (one PFU)	214	MHz

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

## Derating Logic Timing

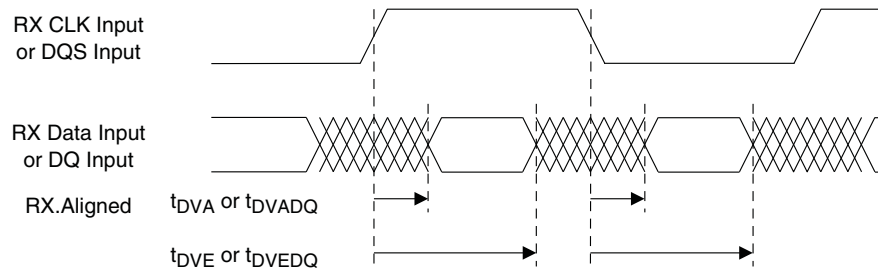
Logic timing provided in the following sections of the data sheet and the Lattice design tools are worst case numbers in the operating range. Actual delays may be much faster. Lattice design tools can provide logic timing numbers at a particular temperature and voltage.

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Generic DDRX2 Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX2_TX.ECLK.Centered <sup>9, 12</sup>									
t <sub>DVB</sub>	Output Data Valid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only	1.445	—	1.760	—	2.140	—	ns
t <sub>DVA</sub>	Output Data Valid After CLK Output		1.445	—	1.760	—	2.140	—	ns
f <sub>DATA</sub>	DDRX2 Serial Output Data Speed		—	280	—	234	—	194	Mbps
f <sub>DDRX2</sub>	DDRX2 ECLK Frequency (minimum limited by PLL)		—	140	—	117	—	97	MHz
f <sub>SCLK</sub>	SCLK Frequency		—	70	—	59	—	49	MHz
Generic DDRX4 Outputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDRX4_TX.ECLK.Aligned <sup>9, 12</sup>									
t <sub>DIA</sub>	Output Data Invalid After CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only	—	0.270	—	0.300	—	0.330	ns
t <sub>DIB</sub>	Output Data Invalid Before CLK Output		—	0.270	—	0.300	—	0.330	ns
f <sub>DATA</sub>	DDRX4 Serial Output Data Speed		—	420	—	352	—	292	Mbps
f <sub>DDRX4</sub>	DDRX4 ECLK Frequency		—	210	—	176	—	146	MHz
f <sub>SCLK</sub>	SCLK Frequency		—	53	—	44	—	37	MHz
Generic DDRX4 Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDRX4_TX.ECLK.Centered <sup>9, 12</sup>									
t <sub>DVB</sub>	Output Data Valid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only	0.873	—	1.067	—	1.319	—	ns
t <sub>DVA</sub>	Output Data Valid After CLK Output		0.873	—	1.067	—	1.319	—	ns
f <sub>DATA</sub>	DDRX4 Serial Output Data Speed		—	420	—	352	—	292	Mbps
f <sub>DDRX4</sub>	DDRX4 ECLK Frequency (minimum limited by PLL)		—	210	—	176	—	146	MHz
f <sub>SCLK</sub>	SCLK Frequency		—	53	—	44	—	37	MHz
7:1 LVDS Outputs – GDDR71_TX.ECLK.7:1 <sup>9, 12</sup>									
t <sub>DIB</sub>	Output Data Invalid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	—	0.240	—	0.270	—	0.300	ns
t <sub>DIA</sub>	Output Data Invalid After CLK Output		—	0.240	—	0.270	—	0.300	ns
f <sub>DATA</sub>	DDR71 Serial Output Data Speed		—	420	—	352	—	292	Mbps
f <sub>DDR71</sub>	DDR71 ECLK Frequency		—	210	—	176	—	146	MHz
f <sub>CLKOUT</sub>	7:1 Output Clock Frequency (SCLK) (minimum limited by PLL)		—	60	—	50	—	42	MHz

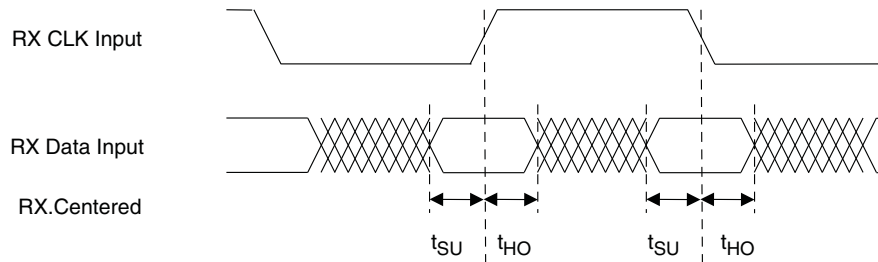
Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
LPDDR <sup>9, 12</sup>									
t <sub>DVADQ</sub>	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. <sup>13</sup>	—	0.349	—	0.381	—	0.396	UI
t <sub>DVEDQ</sub>	Input Data Hold After DQS Input		0.665	—	0.630	—	0.613	—	UI
t <sub>DQVBS</sub>	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t <sub>DQVAS</sub>	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f <sub>DATA</sub>	MEM LPDDR Serial Data Speed		—	120	—	110	—	96	Mbps
f <sub>SCLK</sub>	SCLK Frequency		—	60	—	55	—	48	MHz
f <sub>LPDDR</sub>	LPDDR Data Transfer Rate		0	120	0	110	0	96	Mbps
DDR <sup>9, 12</sup>									
t <sub>DVADQ</sub>	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. <sup>13</sup>	—	0.347	—	0.374	—	0.393	UI
t <sub>DVEDQ</sub>	Input Data Hold After DQS Input		0.665	—	0.637	—	0.616	—	UI
t <sub>DQVBS</sub>	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t <sub>DQVAS</sub>	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f <sub>DATA</sub>	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f <sub>SCLK</sub>	SCLK Frequency		—	70	—	58	—	49	MHz
f <sub>MEM_DDR</sub>	MEM DDR Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps
DDR2 <sup>9, 12</sup>									
t <sub>DVADQ</sub>	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. <sup>13</sup>	—	0.372	—	0.394	—	0.410	UI
t <sub>DVEDQ</sub>	Input Data Hold After DQS Input		0.690	—	0.658	—	0.618	—	UI
t <sub>DQVBS</sub>	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t <sub>DQVAS</sub>	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f <sub>DATA</sub>	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f <sub>SCLK</sub>	SCLK Frequency		—	70	—	58	—	49	MHz
f <sub>MEM_DDR2</sub>	MEM DDR2 Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps

- Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.
- General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0 pF load, fast slew rate.
- Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).
- DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18. LPDDR timing numbers based in LVCMOS18.
- 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).
- For Generic DDRX1 mode  $t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 \text{ ns})/2$ .
- The  $t_{SU\_DEL}$  and  $t_{H\_DEL}$  values use the SCLK\_ZERHOLD default step size. Each step is 167 ps (–3), 182 ps (–2), 195 ps (–1).
- This number for general purpose usage. Duty cycle tolerance is +/-10%.
- Duty cycle is +/- 5% for system usage.
- The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.
- High-speed DDR and LVDS not supported in SG32 (32-Pin QFN) packages.
- Advance information for MachXO2 devices in 48 QFN packages.
- DDR memory interface not supported in QN84 (84 QFN) and SG32 (32 QFN) packages.

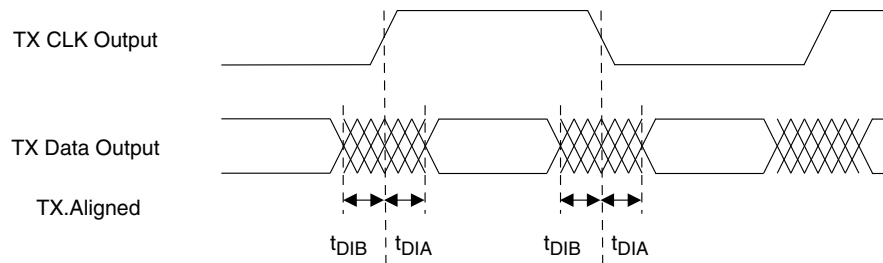
**Figure 3-5. Receiver RX.CLK.Aligned and MEM DDR Input Waveforms**



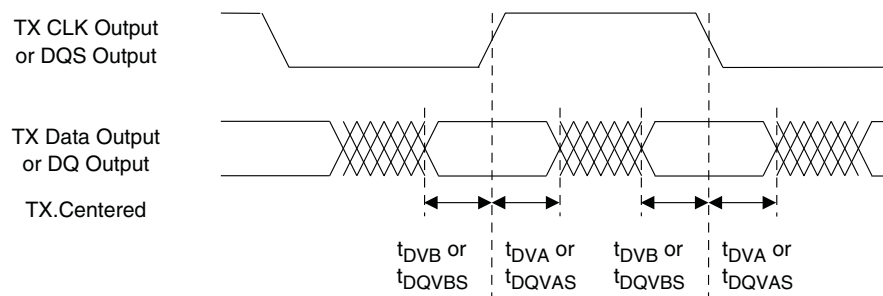
**Figure 3-6. Receiver RX.CLK.Centered Waveforms**



**Figure 3-7. Transmitter TX.CLK.Aligned Waveforms**



**Figure 3-8. Transmitter TX.CLK.Centered and MEM DDR Output Waveforms**





## sysCLOCK PLL Timing

### Over Recommended Operating Conditions

Parameter	Descriptions	Conditions	Min.	Max.	Units
$f_{IN}$	Input Clock Frequency (CLKI, CLKFB)		7	400	MHz
$f_{OUT}$	Output Clock Frequency (CLKOP, CLKOS, CLKOS2)		1.5625	400	MHz
$f_{OUT2}$	Output Frequency (CLKOS3 cascaded from CLKOS2)		0.0122	400	MHz
$f_{VCO}$	PLL VCO Frequency		200	800	MHz
$f_{PFD}$	Phase Detector Input Frequency		7	400	MHz
<b>AC Characteristics</b>					
$t_{DT}$	Output Clock Duty Cycle	Without duty trim selected <sup>3</sup>	45	55	%
$t_{DT\_TRIM}^7$	Edge Duty Trim Accuracy		-75	75	%
$t_{PH}^4$	Output Phase Accuracy		-6	6	%
$t_{OPJIT}^{1,8}$	Output Clock Period Jitter	$f_{OUT} > 100$ MHz	—	150	ps p-p
		$f_{OUT} < 100$ MHz	—	0.007	UIPP
	Output Clock Cycle-to-cycle Jitter	$f_{OUT} > 100$ MHz	—	180	ps p-p
		$f_{OUT} < 100$ MHz	—	0.009	UIPP
	Output Clock Phase Jitter	$f_{PFD} > 100$ MHz	—	160	ps p-p
		$f_{PFD} < 100$ MHz	—	0.011	UIPP
	Output Clock Period Jitter (Fractional-N)	$f_{OUT} > 100$ MHz	—	230	ps p-p
		$f_{OUT} < 100$ MHz	—	0.12	UIPP
	Output Clock Cycle-to-cycle Jitter (Fractional-N)	$f_{OUT} > 100$ MHz	—	230	ps p-p
		$f_{OUT} < 100$ MHz	—	0.12	UIPP
$t_{SPO}$	Static Phase Offset	Divider ratio = integer	-120	120	ps
$t_W$	Output Clock Pulse Width	At 90% or 10% <sup>3</sup>	0.9	—	ns
$t_{LOCK}^{2,5}$	PLL Lock-in Time		—	15	ms
$t_{UNLOCK}$	PLL Unlock Time		—	50	ns
$t_{IPJIT}^6$	Input Clock Period Jitter	$f_{PFD} \geq 20$ MHz	—	1,000	ps p-p
		$f_{PFD} < 20$ MHz	—	0.02	UIPP
$t_{HI}$	Input Clock High Time	90% to 90%	0.5	—	ns
$t_{LO}$	Input Clock Low Time	10% to 10%	0.5	—	ns
$t_{STABLE}^5$	STANDBY High to PLL Stable		—	15	ms
$t_{RST}$	RST/RESETM Pulse Width		1	—	ns
$t_{RSTREC}$	RST Recovery Time		1	—	ns
$t_{RST\_DIV}$	RESETC/D Pulse Width		10	—	ns
$t_{RSTREC\_DIV}$	RESETC/D Recovery Time		1	—	ns
$t_{ROTATE-SETUP}$	PHASESTEP Setup Time		10	—	ns

## Flash Download Time<sup>1, 2</sup>

Symbol	Parameter	Device	Typ.	Units
$t_{\text{REFRESH}}$	POR to Device I/O Active	LCMXO2-256	0.6	ms
		LCMXO2-640	1.0	ms
		LCMXO2-640U	1.9	ms
		LCMXO2-1200	1.9	ms
		LCMXO2-1200U	1.4	ms
		LCMXO2-2000	1.4	ms
		LCMXO2-2000U	2.4	ms
		LCMXO2-4000	2.4	ms
		LCMXO2-7000	3.8	ms

1. Assumes sysMEM EBR initialized to an all zero pattern if they are used.

2. The Flash download time is measured starting from the maximum voltage of POR trip point.

## JTAG Port Timing Specifications

Symbol	Parameter	Min.	Max.	Units
$f_{\text{MAX}}$	TCK clock frequency	—	25	MHz
$t_{\text{BTCPH}}$	TCK [BSCAN] clock pulse width high	20	—	ns
$t_{\text{BTCPL}}$	TCK [BSCAN] clock pulse width low	20	—	ns
$t_{\text{BTS}}$	TCK [BSCAN] setup time	10	—	ns
$t_{\text{BTH}}$	TCK [BSCAN] hold time	8	—	ns
$t_{\text{BTCO}}$	TAP controller falling edge of clock to valid output	—	10	ns
$t_{\text{BTCODIS}}$	TAP controller falling edge of clock to valid disable	—	10	ns
$t_{\text{BTCOEN}}$	TAP controller falling edge of clock to valid enable	—	10	ns
$t_{\text{BTCRS}}$	BSCAN test capture register setup time	8	—	ns
$t_{\text{BTCRH}}$	BSCAN test capture register hold time	20	—	ns
$t_{\text{BUTCO}}$	BSCAN test update register, falling edge of clock to valid output	—	25	ns
$t_{\text{BTUODIS}}$	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
$t_{\text{BTUPOEN}}$	BSCAN test update register, falling edge of clock to valid enable	—	25	ns

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000ZE-1UWG49ITR <sup>1</sup>	2112	1.2 V	–1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1UWG49ITR50 <sup>3</sup>	2112	1.2 V	–1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1UWG49ITR1K <sup>2</sup>	2112	1.2 V	–1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1TG100I	2112	1.2 V	–1	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-2TG100I	2112	1.2 V	–2	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-3TG100I	2112	1.2 V	–3	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-1MG132I	2112	1.2 V	–1	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-2MG132I	2112	1.2 V	–2	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-3MG132I	2112	1.2 V	–3	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-1TG144I	2112	1.2 V	–1	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-2TG144I	2112	1.2 V	–2	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-3TG144I	2112	1.2 V	–3	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-1BG256I	2112	1.2 V	–1	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-2BG256I	2112	1.2 V	–2	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-3BG256I	2112	1.2 V	–3	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-1FTG256I	2112	1.2 V	–1	Halogen-Free ftBGA	256	IND
LCMXO2-2000ZE-2FTG256I	2112	1.2 V	–2	Halogen-Free ftBGA	256	IND
LCMXO2-2000ZE-3FTG256I	2112	1.2 V	–3	Halogen-Free ftBGA	256	IND

1. This part number has a tape and reel quantity of 5,000 units with a minimum order quantity of 10,000 units. Order quantities must be in increments of 5,000 units. For example, a 10,000 unit order will be shipped in two reels with one reel containing 5,000 units and the other reel with less than 5,000 units (depending on test yields). Unserviced backlog will be canceled.
2. This part number has a tape and reel quantity of 1,000 units with a minimum order quantity of 1,000. Order quantities must be in increments of 1,000 units. For example, a 5,000 unit order will be shipped as 5 reels of 1000 units each.
3. This part number has a tape and reel quantity of 50 units with a minimum order quantity of 50. Order quantities must be in increments of 50 units. For example, a 1,000 unit order will be shipped as 20 reels of 50 units each.

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000ZE-1QN84I	4320	1.2 V	–1	Halogen-Free QFN	84	IND
LCMXO2-4000ZE-2QN84I	4320	1.2 V	–2	Halogen-Free QFN	84	IND
LCMXO2-4000ZE-3QN84I	4320	1.2 V	–3	Halogen-Free QFN	84	IND
LCMXO2-4000ZE-1MG132I	4320	1.2 V	–1	Halogen-Free csBGA	132	IND
LCMXO2-4000ZE-2MG132I	4320	1.2 V	–2	Halogen-Free csBGA	132	IND
LCMXO2-4000ZE-3MG132I	4320	1.2 V	–3	Halogen-Free csBGA	132	IND
LCMXO2-4000ZE-1TG144I	4320	1.2 V	–1	Halogen-Free TQFP	144	IND
LCMXO2-4000ZE-2TG144I	4320	1.2 V	–2	Halogen-Free TQFP	144	IND
LCMXO2-4000ZE-3TG144I	4320	1.2 V	–3	Halogen-Free TQFP	144	IND
LCMXO2-4000ZE-1BG256I	4320	1.2 V	–1	Halogen-Free caBGA	256	IND
LCMXO2-4000ZE-2BG256I	4320	1.2 V	–2	Halogen-Free caBGA	256	IND
LCMXO2-4000ZE-3BG256I	4320	1.2 V	–3	Halogen-Free caBGA	256	IND
LCMXO2-4000ZE-1FTG256I	4320	1.2 V	–1	Halogen-Free ftBGA	256	IND
LCMXO2-4000ZE-2FTG256I	4320	1.2 V	–2	Halogen-Free ftBGA	256	IND
LCMXO2-4000ZE-3FTG256I	4320	1.2 V	–3	Halogen-Free ftBGA	256	IND
LCMXO2-4000ZE-1BG332I	4320	1.2 V	–1	Halogen-Free caBGA	332	IND
LCMXO2-4000ZE-2BG332I	4320	1.2 V	–2	Halogen-Free caBGA	332	IND
LCMXO2-4000ZE-3BG332I	4320	1.2 V	–3	Halogen-Free caBGA	332	IND
LCMXO2-4000ZE-1FG484I	4320	1.2 V	–1	Halogen-Free fpBGA	484	IND
LCMXO2-4000ZE-2FG484I	4320	1.2 V	–2	Halogen-Free fpBGA	484	IND
LCMXO2-4000ZE-3FG484I	4320	1.2 V	–3	Halogen-Free fpBGA	484	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000ZE-1TG144I	6864	1.2 V	–1	Halogen-Free TQFP	144	IND
LCMXO2-7000ZE-2TG144I	6864	1.2 V	–2	Halogen-Free TQFP	144	IND
LCMXO2-7000ZE-3TG144I	6864	1.2 V	–3	Halogen-Free TQFP	144	IND
LCMXO2-7000ZE-1BG256I	6864	1.2 V	–1	Halogen-Free caBGA	256	IND
LCMXO2-7000ZE-2BG256I	6864	1.2 V	–2	Halogen-Free caBGA	256	IND
LCMXO2-7000ZE-3BG256I	6864	1.2 V	–3	Halogen-Free caBGA	256	IND
LCMXO2-7000ZE-1FTG256I	6864	1.2 V	–1	Halogen-Free ftBGA	256	IND
LCMXO2-7000ZE-2FTG256I	6864	1.2 V	–2	Halogen-Free ftBGA	256	IND
LCMXO2-7000ZE-3FTG256I	6864	1.2 V	–3	Halogen-Free ftBGA	256	IND
LCMXO2-7000ZE-1BG332I	6864	1.2 V	–1	Halogen-Free caBGA	332	IND
LCMXO2-7000ZE-2BG332I	6864	1.2 V	–2	Halogen-Free caBGA	332	IND
LCMXO2-7000ZE-3BG332I	6864	1.2 V	–3	Halogen-Free caBGA	332	IND
LCMXO2-7000ZE-1FG484I	6864	1.2 V	–1	Halogen-Free fpBGA	484	IND
LCMXO2-7000ZE-2FG484I	6864	1.2 V	–2	Halogen-Free fpBGA	484	IND
LCMXO2-7000ZE-3FG484I	6864	1.2 V	–3	Halogen-Free fpBGA	484	IND

Date	Version	Section	Change Summary
May 2011	01.3	Multiple	Replaced “SED” with “SRAM CRC Error Detection” throughout the document.
		DC and Switching Characteristics	Added footnote 1 to Program Erase Specifications table.
		Pinout Information	Updated Pin Information Summary tables.
			Signal name SO/SISPISO changed to SO/SPISO in the Signal Descriptions table.
April 2011	01.2	—	Data sheet status changed from Advance to Preliminary.
		Introduction	Updated MachXO2 Family Selection Guide table.
		Architecture	Updated Supported Input Standards table.
			Updated sysMEM Memory Primitives diagram.
			Added differential SSTL and HSTL IO standards.
		DC and Switching Characteristics	Updates following parameters: POR voltage levels, DC electrical characteristics, static supply current for ZE/HE/HC devices, static power consumption contribution of different components – ZE devices, programming and erase Flash supply current.
			Added VREF specifications to sysIO recommended operating conditions.
			Updating timing information based on characterization.
			Added differential SSTL and HSTL IO standards.
		Ordering Information	Added Ordering Part Numbers for R1 devices, and devices in WLCSP packages.
			Added R1 device specifications.
January 2011	01.1	All	Included ultra-high I/O devices.
		DC and Switching Characteristics	Recommended Operating Conditions table – Added footnote 3.
			DC Electrical Characteristics table – Updated data for $I_{IL}$ , $I_{IH}$ , $V_{HYST}$ typical values updated.
			Generic DDRX2 Outputs with Clock and Data Aligned at Pin (GDDR2_TX.ECLK.Aligned) Using PCLK Pin for Clock Input tables – Updated data for $T_{DIA}$ and $T_{DIB}$ .
			Generic DDRX4 Outputs with Clock and Data Aligned at Pin (GDDR4_TX.ECLK.Aligned) Using PCLK Pin for Clock Input tables – Updated data for $T_{DIA}$ and $T_{DIB}$ .
			Power-On-Reset Voltage Levels table - clarified note 3.
			Clarified VCCIO related recommended operating conditions specifications.
			Added power supply ramp rate requirements.
			Added Power Supply Ramp Rates table.
			Updated Programming/Erase Specifications table.
			Removed references to $V_{CCP}$ .
		Pinout Information	Included number of 7:1 and 8:1 gearboxes (input and output) in the pin information summary tables.
			Removed references to $V_{CCP}$ .
November 2010	01.0	—	Initial release.